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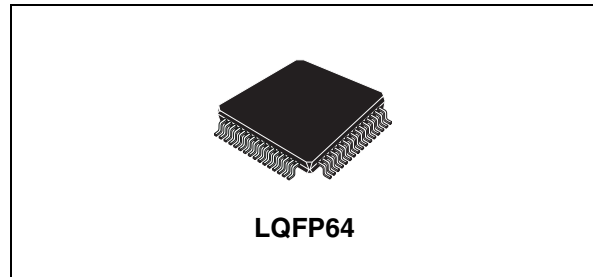
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Octal squib driver and quad sensor interface ASIC for safety application

Features

- 8 deployment drivers sized to deliver 1.2 A (min) for 2 ms (min) and 1.75 A (min) for 1 ms (min)
- Independently controlled high-side and low-side MOS for diagnosis
- Analog output available for resistance
- Squib short to ground, short to battery and MOS diagnostic available on SPI register
- Capability to deploy the squib with 1.2 A (min) or 1.75 A under 35 V load-dump condition and the low side MOS is shorted to ground
- Capability to deploy the squib with 1.2 A (min) at 6.9 V VRES and 1.75 A at 12 V VRES
- Interface with 4 satellite sensors
- Programmable independent current trip points for each satellite channel
- Support Manchester protocol for satellite sensors
- Supports for variable bit rate detection
- Independent current limit and fault timer shutdown protection for each satellite output
- Short to ground and short to battery detection and reporting for each satellite channel
- 5.5 MHz SPI interface
- Satellite message error detection



- Hall effect sensor support on satellite channels 3 and 4.
- Low voltage internal reset
- 2 kV ESD capability on all pins
- Package: 64 leads LQFP
- Technology: ST proprietary BCD5s (0.57 μm)

Description

L9658 is intended to deploy up to 8 squibs and to interface up to 4 satellites. 2 satellite interfaces can be used to interface Hall sensors.

Squib drivers are sized to deploy 1.2 A minimum for 2 ms minimum during load dump and 1.75 A minimum for 1ms minimum during load dump.

Diagnostic of squib driver and squib resistance measurement is controlled by micro controller.

Satellite interfaces support Manchester decoder with variable bit rate.

Table 1. Device summary

Order code	Package	Packing
L9658	LQFP64	Tray
L9658TR	LQFP64	Tape and reel

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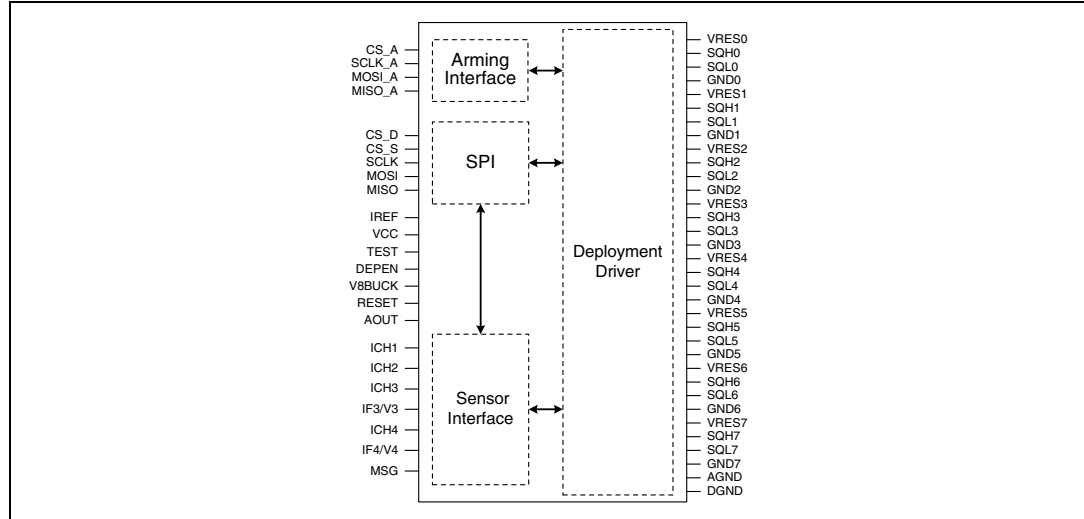
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1 Block diagram and application schematic

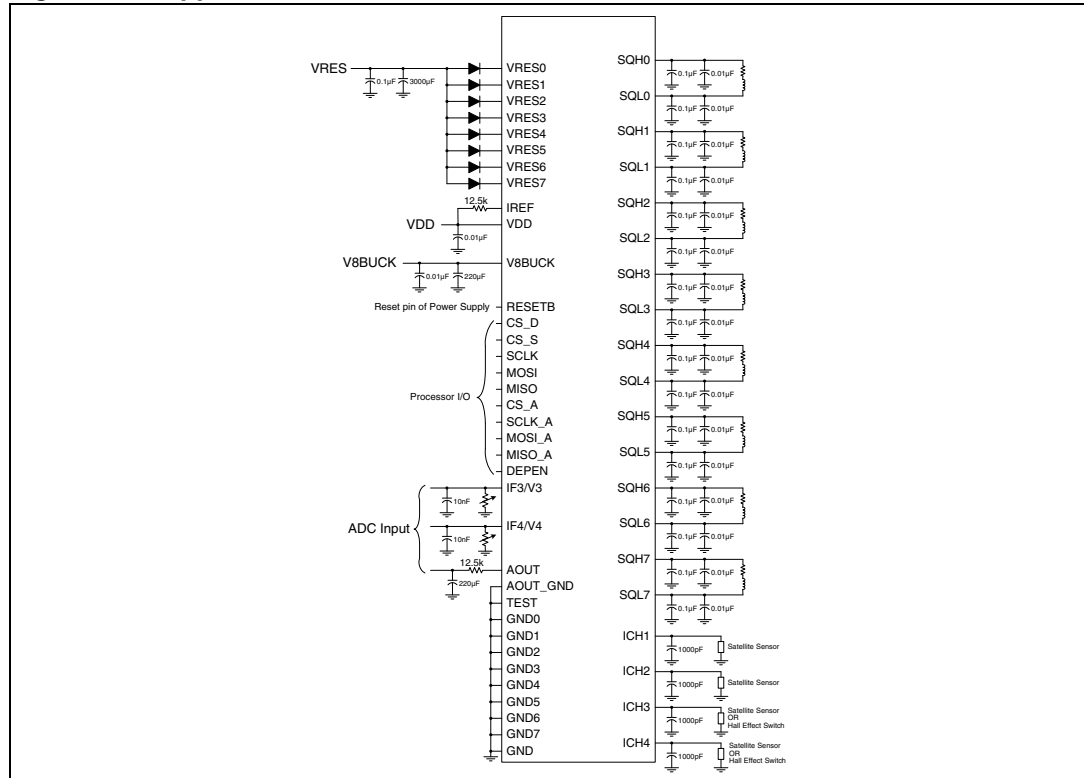
1.1 Block diagram

Figure 1. Block diagram



1.2 Application schematic

Figure 2. Application schematic



2 Pin description

Table 2. Pin function

Pin #	Pin name	Description	I/O type	Reset state
1	MSG	Message waiting	Output	Pull-down
2	MISO	SPI data out	Output	Hi-Z
3	MISO_A	Arming SPI data out	Output	Hi-Z
4	NC	No connect	-	-
5	RESETB	Reset pin	Input	Pull-up
6	GND	Signal ground (analog & digital)	-	-
7	VDD	VDD supply voltage	Input	-
8	NC	No connect	-	-
9	CS_A	SPI chip select for arming interface	Input	Pull-down
10	CS_S	SPI chip select for satellite interface	Input	Pull-down
11	CS_D	SPI chip select for deployment driver	Input	Pull-down
12	DEPEN	Deployment enable	Input	Pull-down
13	MOSI	SPI data in	Input	Hi-Z
14	MOSI_A	Arming SPI data in	Input	Hi-Z
15	SCLK_A	Arming SPI Clock	Input	Hi-Z
16	SCLK	SPI clock	Input	Hi-Z
17	GND4	Power ground for loop channel 4	-	-
18	SQL4	Low side driver output for channel 4	Output	Pull-down
19	SQH4	High side driver output for channel 4	Output	Hi-Z
20	VRES4	Reserve voltage for loop channel 4	Input	-
21	VRES5	Reserve voltage for loop channel 5	Input	-
22	SQH5	High side driver output for channel 5	Output	Hi-Z
23	SQL5	Low side driver output for channel 5	Output	Pull-down
24	GND5	Power ground for loop channel 5	-	-
25	GND6	Power ground for loop channel 6	-	-
26	SQL6	Low side driver output for channel 6	Output	Pull-down
27	SQH6	High side driver output for channel 6	Output	Hi-Z
28	VRES6	Reserve voltage for loop channel 6	Input	-
29	VRES7	Reserve voltage for loop channel 7	Input	-
30	SQH7	High side driver output for channel 7	Output	Hi-Z
31	SQL7	Low side driver output for channel 7	Output	Pull-down
32	GND7	Power ground for loop channel 7	-	-
33	NC	No connect	-	-
34	IF4/V4	Current feedback for channel 4 raw or raw data output for channel 4	Output	Hi-Z
35	IF3/V3	Current feedback for channel 3 raw or data output for channel 3	Output	Hi-Z

Table 2. Pin function (continued)

Pin #	Pin name	Description	I/O type	Reset state
36	NC	No Connect	-	-
37	TEST	Test pin	Input	Pull-down
38	V8BUCK	Supply voltage for satellite interface and resistance measurement	Input	-
39	NC	No Connect	-	-
40	ICH4	Current sense output for channel 4	Output	Hi-Z
41	ICH3	Current sense output for channel 3	Output	Hi-Z
42	ICH2	Current sense output for channel 2	Output	Hi-Z
43	ICH1	Current sense output for channel 1	Output	Hi-Z
44	NC	No connect	-	-
45	IREF	External current reference resistor	Output	-
46	AOUT_GND	Ground reference for AOUT	-	-
47	AOUT	Analog output for loop diagnostics	Output	Hi-Z
48	NC	No Connect	-	-
49	GND3	Power ground for loop channel 3	-	-
50	SQL3	Low side driver output for channel 3	Output	Pull-down
51	SQH3	High side driver output for channel 3	Output	Hi-Z
52	VRES3	Reserve voltage for loop channel 3	Input	-
53	VRES2	Reserve voltage for loop channel 2	Input	-
54	SQH2	High side driver output for channel 2	Output	Hi-Z
55	SQL2	Low side driver output for channel 2	Output	Pull-down
56	GND2	Power ground for loop channel 2	-	-
57	GND1	Power ground for loop channel 1	-	-
58	SQL1	Low side driver output for channel 1	Output	Pull-down
59	SQH1	High Side Driver Output for Channel 1	Output	Hi-Z
60	VRES1	Reserve voltage for loop channel 1	Input	-
61	VRES0	Reserve voltage for loop channel 0	Input	-
62	SQH0	High side driver output for channel 0	Output	Hi-Z
63	SQL0	Low side driver output for channel 0	Output	Pull-down
64	GND0	Power ground for loop channel 0	-	-

2.1 Thermal data

Table 3. Thermal Data

Symbol	Parameter	Value.	Unit
$R_{th\ j-amb}$	Thermal resistance junction-to-ambient	68	°C/W

3 Electrical specification

3.1 Maximum ratings

The device may not operate properly if maximum operating condition is exceeded.

Table 4. Maximum operating conditions

Symbol	Parameter	Value	Unit
V_{DD}	Supply voltage	4.9 to 5.1	V
V_{8BUCK}	V8BUCK voltage	7 to 8.5	V
V_{RES}	VRES voltage (VRES0, VRES1, VRES2, VRES3, VRES4, VRES5, VRES6, VRES7)	35	V
V_I	Discrete input voltage (RESETB, DEPEND, CS_A, CS_D, CS_S, SCLK, SCLK_A, MOSI, MOSI_A, MISO, MISO_A)	-0.3 to ($V_{DD} + 0.3$)	V
T_j	Junction temperature	-40 to 150	°C

3.2 Absolute maximum ratings

Caution: Maximum ratings are absolute ratings; exceeding any one of these values may cause permanent damage to the integrated circuit.

Table 5. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DD}	Supply voltage	-0.3 to 5.5	V
V_{8BUCK}	V8BUCK voltage	-0.3 to 40	V
V_{RES}	VRES Voltage (VRES0, VRES1, VRES2, VRES3, VRES4, VRES5, VRES6, VRES7)	-0.3 to 40	V
S_{QL-H}	Squib high and low side drivers (SQH0, SQH1, SQH2, SQH3, SQH4, SQH5, SQH6, SQH7, SQL0, SQL1, SQL2, SQL3, SQL4, SQL5, SQL6, SQL7)	-0.3 to 40	V
V_I	Discrete input voltage (RESETB, DEPEND, CS_A, CS_D, CS_S, SCLK, SCLK_A, MOSI, MOSI_A, MISO, MISO_A)	-0.3 to 5.5	V
ICHx	Satellite input voltage (ICH1, ICH2, ICH3, ICH4)	-3 to 40	V
-	Analog/digital outputs voltage (AOUT, IREF, MSG, IF3V3, IF4V4)	-0.3 to 5.5	V
GNDx	Ground pins voltage (GND, AOUT_GND, GND0, GND1, GND2, GND3, GND4, GND5, GND6, GND7)	-0.3 to 5.5	V
T_j	Maximum steady-state junction temperature	150	°C
T_{amb}	Ambient temperature	-40 to 95	°C
T_{stg}	Storage temperature	-65 to 150	°C

3.3 Electrical characteristics

3.3.1 DC characteristics

$V_{RES} = 6.5$ to 35 V, $V_{DD} = 4.9$ to 5.1 V, $V_{8BUCK} = 7.0$ V to 8.5 V, $T_{amb} = -40$ °C to $+95$ °C

Table 6. DC specification general

Symbol	Parameter	Test condition	Min.	Typ	Max.	Unit
$V_{RST}^{(1)}$	Internal voltage reset V_{DD}	V_{DD} drops until deployment drivers are disabled	4.0	-	4.5	V
$V_{RST_L}^{(2)}$			2.1	-	3.0	
I_{DD}	Input current V_{DD}	Normal operation; $I_{CH1-4} = 0$ A	6.2	-	8.6	mA
		Short to -0.3 V on SQH; $I_{CH1-4} = 0$ A	5.5	-	9.5	
		Short to -0.3 V on SQL; $I_{CH1-4} = 0$ A	5.5	-	9.5	
		Deployment; $I_{CH1-4} = 0$ A	5.5	-	9.5	
R_{IREF_H}	Resistance threshold I_{REF}	-	20.0	-	60.0	k Ω
R_{IREF_L}		-	2.0	-	9.0	k Ω
V_{IH_RESETB}	Input voltage threshold RESETB	-	-	-	2.0	V
V_{IL_RESETB}		-	0.8	-	-	V
V_{HYS}		-	100	-	400	mV
V_{IH_DEPEN}	Input voltage threshold DEPEN	-	-	-	2.0	V
V_{IL_DEPEN}		-	0.8	-	-	V
I_{PD}	Input pull-down current DEPEN	$V_{IN} = V_{IL}$ to V_{DD}	10	-	50	μ A
V_{IH_TEST}	Input voltage threshold TEST	-	-	-	3.6	V
V_{IL_TEST}		-	0.8	-	-	V
I_{TEST}	Input pull-down current TEST	TEST = 5 V	1.0	-	2.5	mA
I_{PU}	Input pull-up current RESETB	RESETB = V_{IH} to GND	10	-	60	μ A
I_{V8BUCK}	Current consumption V8BUCK	-	25	-	40	μ A
V_{IH}	Input voltage threshold MOSI, MOSI_A, SCLK, SCLK_A, CS_S, CS_D, CS_A	Input logic = 1	-	-	2.0	V
V_{IL}		Input logic = 0	0.8	-	-	V
V_{HYS}		-	100	-	400	mV
I_{LKG}	Input leakage current MOSI, MOSI_A, SCLK, SCLK_A	$V_{IN} = V_{DD}$	-	-	1	μ A
		$V_{IN} = 0$ to V_{IH}	-1	-	-	μ A
I_{PD}	Input pull-down current CS_S, CS_D, CS_A	$V_{IN} = V_{IL}$ to V_{DD}	10	-	50	μ A
V_{OH}	Output voltage MISO, MISO_A, MSG	$I_{OH} = -800$ μ A	$V_{DD}-0.8$	-	-	V
V_{OL}		$I_{OL} = 1.6$ mA	-	-	0.4	V
I_{HI_Z}	Tri-state current MISO, MISO_A,	MISO = VDD	-	-	1	μ A
		MISO = 0 V	-1	-	-	μ A

- V_{RST} shall have a POR de-glitch timer.
- V_{RST_L} shall have no timer.

$V_{RES} = 6.5$ to 35 V, $V_{DD} = 4.9$ to 5.1 V, $V_{8BUCK} = 7.0$ V to 8.5 V, $T_{amb} = -40$ °C to $+95$ °C

Table 7. DC Specification: deployment drivers

Symbol	Parameter	Test conditions	Min.	Typ	Max.	Units
V_{OH}	Output voltage AOUT	High saturation voltage; $I_{AOUT} = -500 \mu A$	$V_{DD} - 0.4$	-	-	V
V_{OL}		Low saturation voltage; $I_{AOUT} = +500 \mu A$	-	-	0.3	V
I_Z	Tri-state current AOUT	AOUT = V_{DD}	-	-	1	μA
		AOUT = 0 V	-1	-	-	μA
I_{LKG}	Leakage current SQH	$V_{8BUCK} = V_{DD} = 0$, $V_{RES} = 36$ V, $V_{SQH} = 0$ V	-	-	50	μA
I_{STG}		$V_{8BUCK} = 18$ V; $V_{DD} = 5$ V; $V_{SQH} = -0.3$ V	-5	-	-	mA
I_{LKG}	Bias current VRES ⁽¹⁾	$V_{8BUCK} = 18$ V; $V_{DD} = 5$ V; $V_{RES} = 36$ V; SQH shorted to SQL	-	-	10	μA
I_{LKG}	Leakage current SQL	$V_{8BUCK} = V_{DD} = 0$, $V_{SQL} = 18$ V	-10	-	10	μA
I_{STG}		$V_{8BUCK} = 18$ V; $V_{DD} = 5$ V; $V_{SQL} = -0.3$ V	-5	-	-	mA
I_{STB}		$V_{8BUCK} = 18$ V; $V_{DD} = 5$ V; $V_{SQL} = 18$ V	-	-	5	mA
I_{PD}	Pull-down current SQL	$V_{SQL} = 1.8$ V to V_{DD}	900	-	1300	μA
I_{PD_SQH}	Pull-down current SQH	$V_{SQH} = SBTH$ to V_{RES}	900	-	1300	μA
V_{BIAS}	Diagnostics Bias Voltage	$I_{SQH} = -1.5$ mA (nominal: 2.0 V)	1.80	-	2.20	V
I_{BIAS}	Diagnostics Bias Current	$V_{SQH} = 0$ V	-7	-	-	I_{PD}
V_{STB}	Short to battery threshold	(Nominal 3.0 V)	2.70	-	3.30	V
V_{STG}	Short to ground threshold	(Nominal 1.0 V)	0.90	-	1.10	V
V_{I_th}	MOS test load voltage detection	-	100	-	300	mV
I_{SRC}	Resistance measurement current source	$V_{DD} = 5.0$ V; $V_{8BUCK} = 7.0$ V to 26.5 V	38	-	42	mA
I_{SINK}	Resistance measurement current sink	-	45	-	55	mA
R_{DSon}	Total high and low side MOS On resistance	High side MOS + Low Side MOS $V_{RES} = 6.9$ V; $I = 1.2$ A @95 °C	-	-	2.0	Ω
R_{DSon}	High side MOS on resistance	$V_{RES} = 35$ V; $I_{VRES} = 1.2$ A; $T_{amb} = 95$ °C	-	-	0.8	Ω
R_{DSon}	Low side MOS on resistance	$V_{RES} = 35$ V; $I_{VRES} = 1.2$ A; $T_{amb} = 95$ °C	-	-	1.2	Ω
I_{DEPL_12A}	Deployment current	MOSI register mode bit D10="0" $R_{LOAD} = 1.7 \Omega$; $V_{RES} = 6.9$ to 35 V	1.20	-	1.47	A
I_{DEPL_175A}		MOSI register mode bit D10="1" $R_{LOAD} = 1.7 \Omega$; $V_{RES} = 12$ to 35 V	1.75	-	2.14	A
I_{LIM}	Low side MOS current limit	$R_{LOAD} = 1.7 \Omega$	2.15	-	3.5	A
R_{L_RANGE}	Load resistance range ⁽²⁾	-	0	-	10.0	Ω

1. Not applicable during a diagnostic.
2. Test conditions for load resistance measurements

$V_{DD} = 4.9 \text{ to } 5.1 \text{ V}$, $V_{8BUCK} = 7.0 \text{ V to } 8.5 \text{ V}$, $T_{amb} = -40 \text{ }^{\circ}\text{C to } +95 \text{ }^{\circ}\text{C}$
Table 8. Satellite interface DC specifications

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
I_Lim	Current limit	High side short to -0.3 V	(-)75	-	(-)150	mA
		High side short to Battery	-	-	5	mA
		V8BUCK = Vcc=0 measured @ V8BUCK	-	-	-1	mA
Vhdp	High side voltage drop	I=50 mA @ 105 °C; V8BUCK=7.0 V	-	-	1	V
		I=25 mA @ 105 °C; V8BUCK=7.0 V	-	-	0.5	V
IFr	IF/Iout CH3 & CH4	Iout = -50mA	460	-	540	μA
		Iout = -5mA	46	-	54	μA
Itr	Low to high transition current threshold	SPI channel configuration				
		Bit <2:0>≥111	54.00	-	66.00	mA
		Bit <2:0>≥110	43.65	-	53.35	mA
		Bit <2:0>≥101	35.10	-	42.90	mA
		Bit <2:0>≥100	28.80	-	34.20	mA
		Bit <2:0>≥011	24.85	-	29.15	mA
		Bit <2:0>≥010	20.25	-	24.75	mA
		Bit <2:0>≥001	17.10	-	20.90	mA
	Bit <2:0>≥000	14.85	-	18.15	mA	
V_CLAMP	IF/Vx CH3 & CH4 clamp voltage	Rext=33.3 kΩ; CHx is shorted to GND	0.95* Vdd	-	1.05* Vdd	V
Ihyst	Current threshold hysteresis	Sink current = Ithr at the output (ICHX). Ihyst=trip point high – trip point low	0.05*Itr	-	0.15*Itr	mA
Vos	Short to BAT feedback current	V(ICHX)-V8BUCK<50mV	-	-	25	mA
Olkg	Output leakage current ICH _x	V=18 V @ pin under test	-	-	1	μA

3.3.2 AC characteristics

$V_{RES} = 6.5$ to 35 V, $V_{DD} = 4.9$ to 5.1 V, $V_{8BUCK} = 7.0$ V to 8.5 V, $T_{amb} = -40$ °C to $+95$ °C

Table 9. AC specification: deployment drivers

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
t_{POR}	POR de-glitch timer	Timer for V_{RST}	10	-	25	μ s
T_{GLITCH}	De-glitch timer	-	5	-	20	μ s
I_{ON}	Diagnostic current	DEPEN pins asserted; Measured at 150 μ s from falling edge CS_D or CS_A; See Figure 4	0.90	-	-	I_{FINAL}
t_{PULSE}	Pulse stretch timer	See Table 17	0	-	60	ms
t_{P_ACC}	Pulse stretch timer accuracy	-	-20	-	20	%
$t_{DEPLOY-2ms}$	Deployment time	$V_{RES} = 6.9$ to 35 V ⁽¹⁾	2	-	2.5	ms
$t_{DEPLOY-1ms}$	Deployment time	$V_{RES} = 12$ to 40 V ⁽¹⁾	1	-	1.15	ms
t_{FLT_DLY}	Fault detection filter ⁽²⁾	-	10	-	50	μ s
I_{SLEW}	Rmeas current di/dt	10 % - 90 % of I_{SRC}	2	-	8	$\frac{mA}{\mu s}$
t_{R_DLY}	Rmeas current delay	From the falling edge of CS to 10 % of I_{SRC}	-	-	15	μ s
t_{R_WAIT}	Rmeas wait time ⁽²⁾	Wait time before AOUT voltage is stable for ADC reading	-	-	100	μ s
$t_{TIMEOUT}$	MOS diagnostic on-time	-	-	-	2.5	ms
t_{ILIM}	SQL high current protection timer	-	90	-	110	μ s
t_{PROP_DLY}	LS/HS MOS turn off propagation delay ⁽²⁾	Time is measured from the valid LS/HS MOS fault to the LS/HS turn off	-	-	10	μ s

1. Application Information; Test is not performed at high voltage.

2. Design Information Only

Figure 3. MOS settling time and turn-on time 1

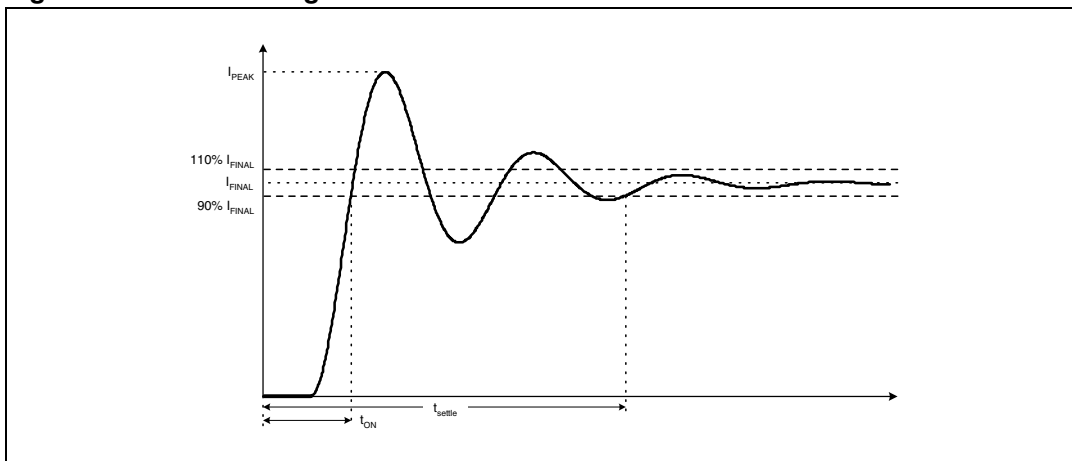
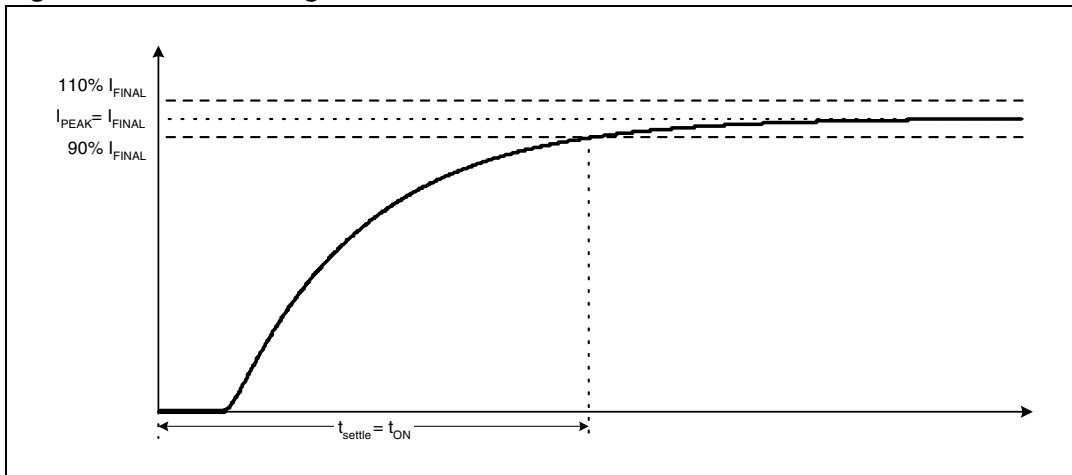


Figure 4. MOS settling time and turn-on time 2



$V_{DD} = 4.9$ to 5.1 V; $V_{8BUCK} = 7.0$ V to 8.5 V, $T_{amb} = -40$ °C to $+95$ °C

Table 10. AC specifications: satellite

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
Osc	Internal oscillator frequency	Tested with 12.5k 1% Iref resistor	4.45		5.55	MHz
Mdf	De-glitch filter as a function of protocol speed	Manchester Protocol Excluding Osc tolerance Bit<8:7≥ 00 Bit<8:7≥ 01 Bit<8:7≥ 10 Bit<8:7≥ 11	11.76 %*Bit-Time	-	23.53 % *Bit-Time	µs
Bitr	Minimum frequency operating range (Incoming messages fall within this operating range is guaranteed to be accepted by the IC)	Channel configurations				
		Bit<8:7≥ 00 Test at frq = 52.33 kHz Test at frq =13.32 kHz	13.32	-	52.33	kHz
		Bit<8:7≥01 Test at frq =110.74 kHz Test at frq = 26.32 kHz	26.32	-	110.74	kHz
		Bit<8:7≥10 Test at frq =164.20 kHz Test at frq = 43.50 kHz	43.50	-	164.20	kHz
		Bit<8:7≥11 Test at frq =250.63 kHz Test at frq = 62.66 kHz	62.66	-	250.63	kHz
Bitr	Maximum frequency operating range (Incoming messages fall outside this operating range is guaranteed to be rejected by the IC)	Channel configurations				
		Bit<8:7≥ 00 Test at frq > 59.14 kHz Test at frq <11.99 kHz	11.99	-	59.14	kHz
		Bit<8:7≥01 Test at frq>128.37 kHz Test at frq <23.57 kHz	23.57	-	128.37	kHz
		Bit<8:7≥10 Test at frq>194.93 kHz Test at frq <38.71 kHz	38.71	-	194.93	kHz
		Bit<8:7≥11 Test at frq>309.6 kHz Test at frq <55.37 kHz	55.37	-	309.6	kHz
Idle	Idle time	Manchester	2	-	-	Bit Times
Tdl & Tdh	IFx/Vx delay	Test with12.5k 1% Iref resistor check response from changing between the following current levels. High =0-15 mA, Low = 66 to 150 mA	-	1	-	µs
Tdl - Tdh	IFx/Vx delay time differential	ICH _x outputs with a 500 µs symmetrical pulse in and 500µs out.	-	-	0.3	µs
Fit	Output fault timer	I_sensor > I_lim	300	-	500	µs

$V_{RES} = 6.5$ to 35 V, $V_{DD} = 4.9$ to 5.1 V. $V_{8BUCK} = 7.0$ V to 8.5 V, $T_{amb} = -40^{\circ}$ C to $+95^{\circ}$ C
 All SPI timing is performed with a 200 pF load on MISO unless otherwise noted.

Table 11. SPI timing

No.	Symbol	Parameter	Min	Typ	Max	Unit
-	f _{op}	Transfer frequency	dc	-	5.50	MHz
1	t _{SCK}	SCLK, SCLK_A Period	181	-	-	ns
2	t _{LEAD}	Enable lead time	65	-	-	ns
3	t _{LAG}	Enable lag time	50	-	-	ns
4	t _{SCLKHS}	SCLK, SCLK_A high time	65	-	-	ns
5	t _{SCLKLS}	SCLK, SCLK_A low time	65	-	-	ns
6	t _{SUS}	MOSI, MOSI_A input setup time	20	-	-	ns
7	t _{HS}	MOSI, MOSI_A input hold time	20	-	-	ns
8	t _A	MISO, MISO_A access time	-	-	60	ns
9	t _{DIS}	MISO, MISO_A disable time ⁽¹⁾	-	-	100	ns
10	t _{VS}	MISO, MISO_A output valid time	-	-	66	ns
11	t _{HO}	MISO, MISO_A output hold time ⁽¹⁾	0	-	-	ns
12	t _{RO}	Rise Time (Design Information)	-	-	30	ns
13	t _{FO}	Fall Time (Design Information)	-	-	30	ns
14	t _{CSN}	CS_A, CS_D, CS_S negated time	640	-	-	ns

1. Parameters t_{DIS} and t_{HO} shall be measured with no additional capacitive load beyond the normal test fixture capacitance on the MISO pin. Additional capacitance during the disable time test erroneously extends the measured output disable time, and minimum capacitance on MISO is the worst case for output hold time.

Figure 5. SPI timing diagram

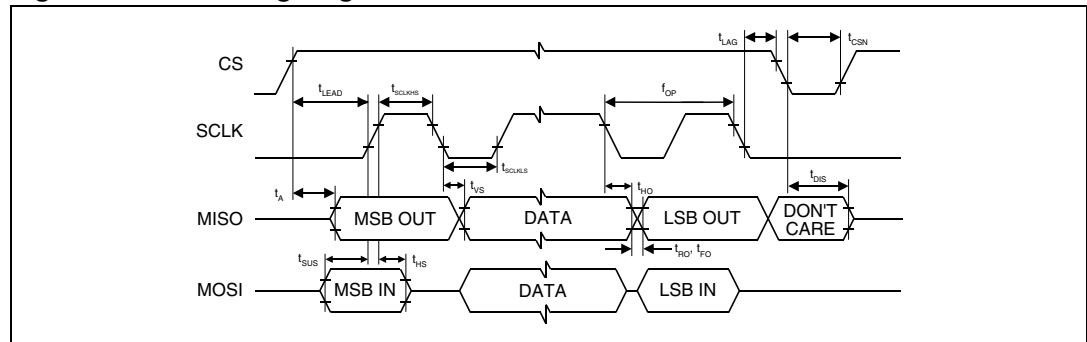
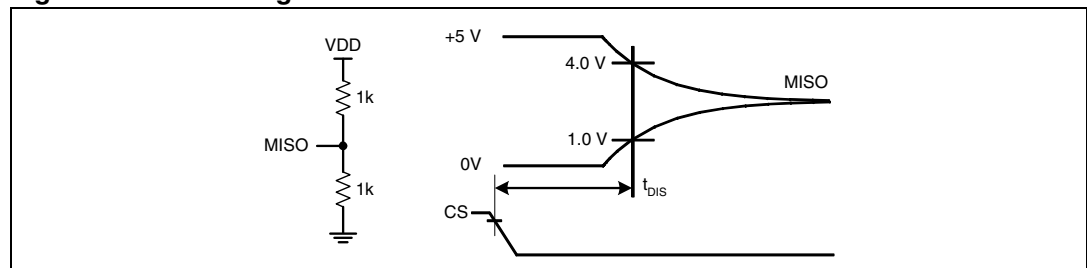


Figure 6. SPI timing measurement



4 Functional description

4.1 Overview

L9658 is an integrated circuit to be used in air bag systems. Its main functions include deployment of air bags, switched-power sources to satellite sensors, diagnostics of SDM (Sensing Deployment Module) and arming inputs. L9658 supports 8 deployment loops, 4 satellite-sensor interfaces, and SPI arming inputs.

4.2 Power on reset (POR)

L9658 has a power on reset (POR) circuit, which monitors V_{DD} voltage. When V_{DD} voltage falls below V_{RST} for longer than or equal to t_{POR} , all outputs are disabled and all internal registers are reset to their default condition.

When V_{DD} falls below V_{RST_L} , all outputs are disabled and all internal registers are reset to their default condition. No delay filter shall be used along with V_{RST_L} threshold.

If V_{DD} voltage falls below V_{RST} for less than t_{POR} , operation shall not be interrupted.

When V_{DD} rises above V_{RST} , the outputs are enabled. Before V_{DD} reaches V_{RST} and during t_{POR} , none of the outputs turn on.

4.3 RESETB

RESETB pin is active low. The effects of RESETB are similar to those of a POR event, except during a deployment. When L9658 has a deployment in-progress, it ignores RESETB signal.

However, it shall shut itself down as soon as it detects a POR condition. When the deployment is completed and RESETB signal is asserted, the device disables its outputs and reset its internal registers to their default states.

A de-glitch timer is provided to RESETB pin. The timer protects this pin against spurious glitches. UT48 neglects RESETB signal if it is asserted for shorter than t_{GLITCH} . RESETB has an internal pull-up in case of an open circuit. This pin has a de-glitch timer

4.4 MSG

MSG pin is used to reflect FIFO status. Its polarity can be configured and also the strategy of activation.

Polling mode: Message pin shall be active as soon as one of the 4 FIFO will be not empty and it will be inactive when all 4 FIFO will be empty. A microcontroller can periodically monitor the status of line to understand there are data received from satellite. Interrupt

mode: Message pin shall be active as soon one of the 4 FIFO will be not empty and it will be inactive when a spi communication on CS_S interface starts. At the end of the SPI communication it shall be active if one of the 4 FIFO will be not empty. Otherwise shall be kept inactive. A microcontroller can wait until an edge is present on the line and manage the data available in the FIFO.

4.5 IREF

I_{REF} pin shall be connected to V_{DD} supply through a resistor, R_{IREF}. When the device detects the resistor on I_{REF} pin is larger than R_{IREF_H} or smaller than R_{IREF_L}, it goes in reset condition. All outputs are disabled and all internal registers are reset to their default conditions.

4.6 Loss of ground

When GND pin is disconnected from PC-board ground, L9658 goes in reset condition. All outputs are disabled and all internal registers are reset to their default conditions. A loss of power-ground (GND0 – GND7) pin/s disables the respective channel/s. In other words, the channel that loses its power ground connection will not be able to deploy. The rest of the device is not affected by a loss of power-ground condition.

A_{OUT_GND} pin is a reference for A_{OUT} pin. When A_{OUT_GND} loses its connection the reset as well.

4.7 Deployment and reset

The following conditions reset and terminate deployments:

- Power On Reset (POR)
- IREF resistance is larger than R_{IREF_H} or smaller than R_{IREF_L}
- Loss of ground condition on GND pin

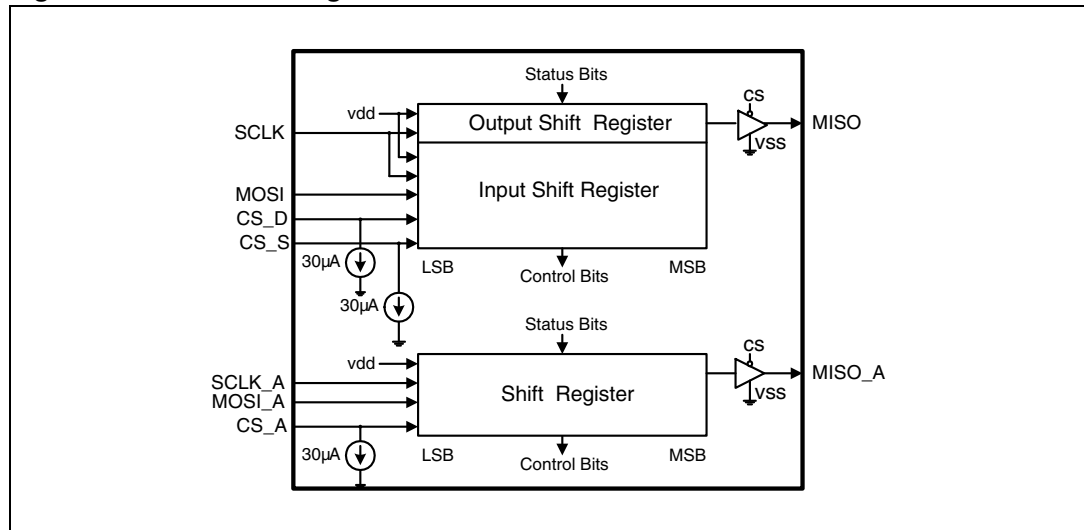
The following conditions are ignored when it has a deployment in-progress:

- RESETB
- Valid soft reset sequences

4.8 Serial peripheral interface (SPI)

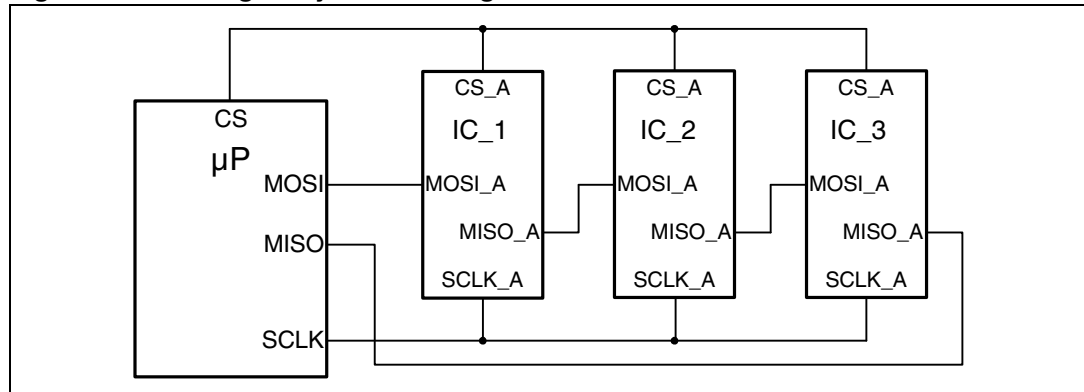
The device contains a serial peripheral interface consisting of Serial Clock (SCLK, SCLK_A), Serial Data Out (MISO, MISO_A), Serial Data In (MOSI, MOSI_A), and two Chip Selects (CS_A, CS_D and CS_S). This device is configured as an SPI slave. The idle state of the communication, Serial Clock (SCLK, SCLK_A) should be low state.

Figure 7. SPI block diagram



L9658 has a counter to verify the number of clocks in SCLK and SCLK_A. If the number of clocks in SCLK is not equal to 16 clocks while CS_D is asserted, it ignores the SPI message and send a SPI fault response. If the number of clocks in SCLK is not equal to 64 clocks while CS_S is asserted, it ignores the entire SPI message and push the Bad SPI Bit Count fault code into the FIFO. If the number of clocks in SCLK_A is not a multiple of 8, it ignores the command in the arming shift register. Otherwise, the device latch-in the command.

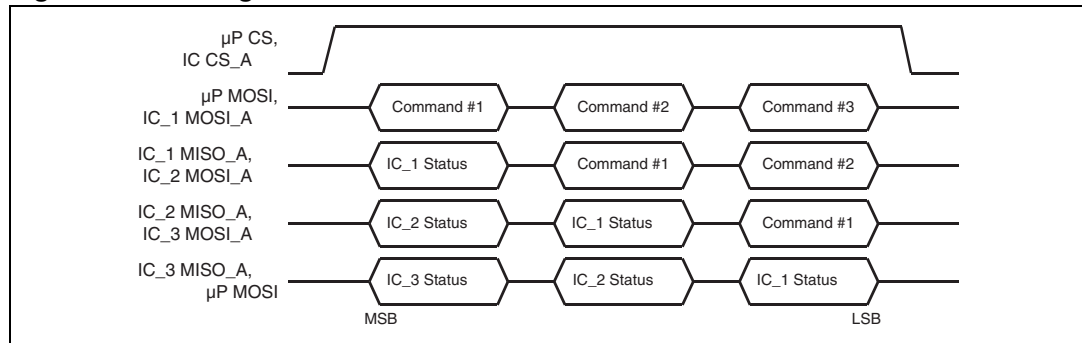
Figure 8. Arming daisy-chain configuration



Arming SPI interface is based on 8-bit data transfer. The device is capable to receive a multiple of 8-bit commands. The first byte of data coming out of MISO_A will be the arming status bits. The subsequent bits will be the arming command bits received through MOSI_A pin. Refer to below figure for an example of arming SPI transmission. This is an example of arming SPI transmission based on the daisy-chain configuration.

In case of daisy chain connection for Arming SPI, device works as following:

All devices IC_1, IC_2, IC_3 shifted out data on the falling edge of SCLK_A for the first 8 bits and shifted out data on the rising edge of SCLK_A for the bits after 8bits. therefore µP, IC_3, IC_2 shall strobe 24bits on rising edge of SCLK_A, the first 8 bits are produced (by IC_3, IC_2, IC_1 respectively) on the falling edge of SCLK_A. the remaining 16 bits are shifted out on the rising edge.

Figure 9. Arming SPI transmission

4.8.1 Chip select (CS_A, CS_D, CS_S)

Chip-select inputs select L9658 for serial transfers. CS_A is independent to CS_D and CS_S.

CS_A can be asserted regardless of CS_D and CS_S. However, either CS_D or CS_S can be asserted at any given time. If both CS_D and CS_S inputs are selected simultaneously, the device ignores MOSI command. When chip-select is asserted, the respective MISO/MISO_A pin is released from tri-state mode, and all status information is latched in the SPI shift register. While chip-select is asserted, register data is shifted into MOSI/MOSI_A pin and shifted out of MISO/MISO_A pin on each subsequent SCLK/SCLK_A. When chip-select is negated, MISO/MISO_A pin is tri-stated. To allow sufficient time to reload the registers; chip-select pin shall remain negated for at least t_{CSN} .

Chip-select is also immune to spurious pulses of 50 ns or shorter (MISO/MISO_A may come out of tri-state, but no status bits is cleared and no control bits is changed).

Chip-select inputs have current sinks on the pins, which pull these pins to the negated state when an open circuit condition occur. These pins have TTL level compatible input voltages allowing proper operation with microprocessors using a 3.3 to 5.0 V supply.

4.8.2 Serial clock (SCLK, SCLK_A)

SCLK/SCLK_A input is the clock signal input for synchronization of serial data transfer. This pin has TTL level compatible input voltages allowing proper operation with microprocessors using a 3.3 to 5.0 V supply. When chip select is asserted, both the SPI master and this device shall latch input data on the rising edge of SCLK/SCLK_A. L9658 shift data out on the falling edge of SCLK/SCLK_A. The SCLK/SCLK_A must be taken in idle state (LOW) when the CS_A, CS_D, CS_S are in idle state (LOW).^(a)

4.8.3 Serial data output (MISO, MISO_A)

MISO/MISO_A output pin shall be in a tri-state condition when chip select is negated. When chip select is asserted, the MSB is the first bit of the word/byte transmitted on MISO/MISO_A and the LSB is the last bit of the word/byte transmitted. This pin supplies a rail to rail output, so if interfaced to a microprocessor that is using a lower VDD supply, the appropriate microprocessor input pin shall not sink more than IOH (min) and shall not clamp the MISO/MISO_A output voltage to less than VOH (min) while MISO/MISO_A pin is in a logic "1" state.

a. Only in daisy chain, it is needed to guarantee on SCLK_A a clock skew of 3ns maximum between any devices.

4.8.4 Serial data input (MOSI, MOSI_A)

MOSI/MOSI_A input takes data from the master processor while chip select is asserted.

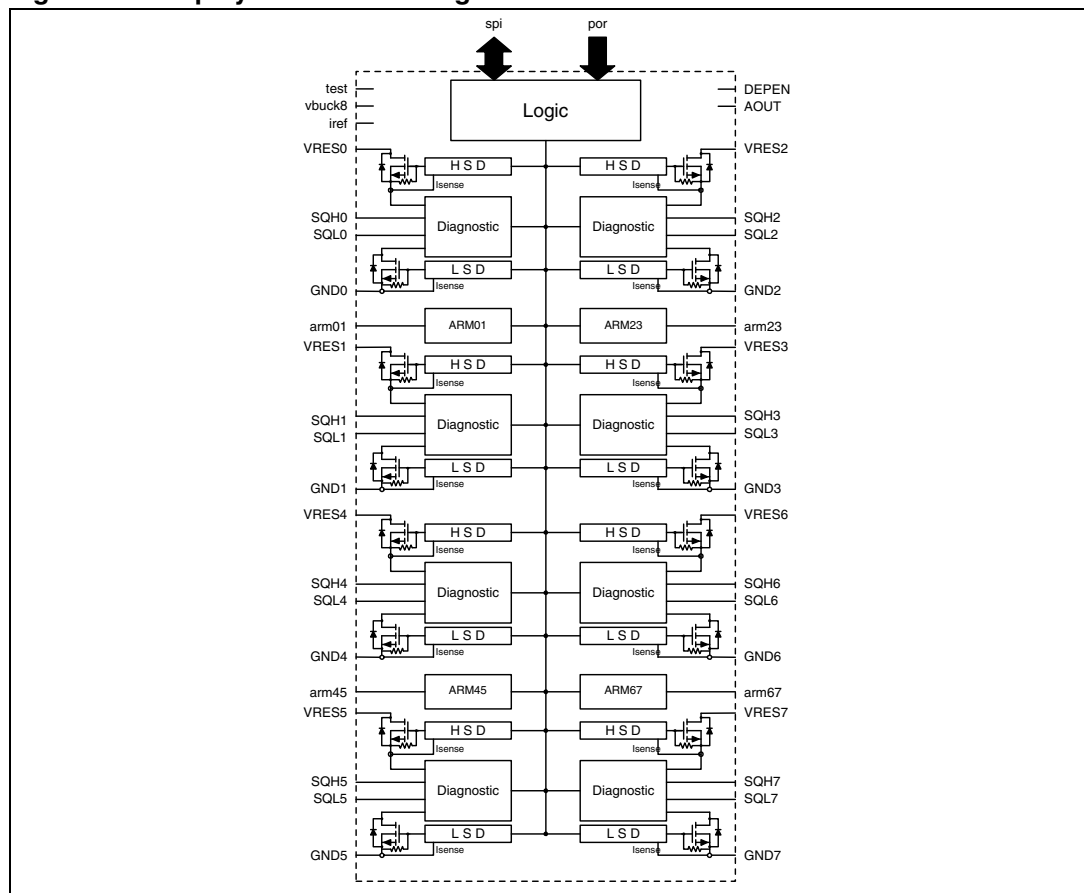
The MSB shall be the first bit of each word/byte received on MOSI/MOSI_A and the LSB shall be the last bit of each word/byte received. This pin has TTL level compatible input voltages allowing proper operation with microprocessors using a 3.3 to 5.0 V supply.

4.9 Deployment drivers

The on-chip deployment drivers are designed to deliver 1.2 A (min) at 6.9 V VRES. Deployment current is be 1.2 A (min) for 2 ms (min). The high side driver survives deployment with 1.47 A, 35 V at VRES and SQL is shorted to ground for 2.5ms. Minimum load resistance is 1.7. At the end of a deployment, a deploy success flag is asserted via SPI. Each VRES and GND connection are used to accommodate 8 loops that can be deployed simultaneously.

Upon receiving a valid deployment condition, the respective SQH and SQL drivers are turned on. SQH and SQL drivers are also turned on momentarily during a MOS diagnostic. Otherwise, SQH and SQL are inactive under any normal, fault, or transient conditions. Upon a successful deployment of the respective SQH and SQL drivers, a deploy command success flag is asserted via SPI. Refer to "deployment sequence" figure for the valid condition and the deploy success flag timing.

Figure 10. Deployment drivers diagram



The following power-up conditions is considered as normal operations. VRES input can be connected to either a power supply output or an ignition voltage. VDD is connected to 5 V output of power supply. When VRES is connected to the power supply, VDD voltage will reach its regulation voltage before VRES voltage is stabilized. In this condition, the device has the control of its internal logic and that prevent an inadvertent turn-on of the drivers.

When VRES is connected to the ignition, VRES voltage will be stabilized before VDD reaches its regulation voltage. In this condition, all drivers are inactive. A pull-down on the gates of high side drivers (SQH) is provided to prevent these drivers from momentarily turning-on. Any loop driver fault conditions do not turn on the SQH and SQL drivers. Only a valid deployment condition can turn on the respective SQH and SQL drivers. Refer to section for valid deployment conditions.

4.9.1 Arming interface

The arming interface is used as a fail-safe to prevent inadvertent airbag deployment. Along with deployment command, these signals provide redundancy. Pulse stretch timer is provided for each channel/loop. Either ARM signal or deployment command shall start the pulse stretch timer.

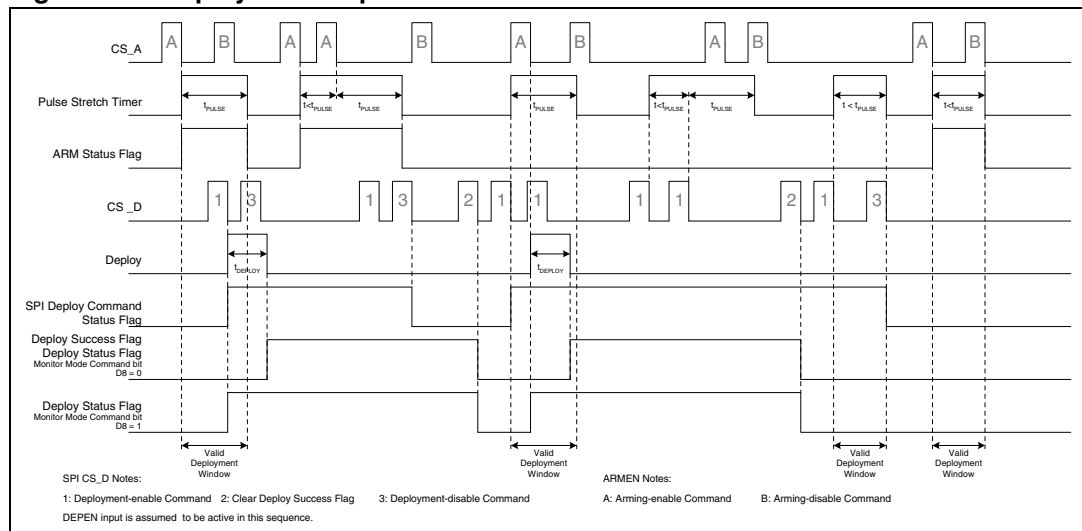
Arming interface has a dedicated 8-bit SPI interface.

When CS_A is negated, L9658 latch ARM signal from the shift register and start the pulse stretch timer for the respective channel/s. The device can deploy a channel, ONLY when DEPEN is asserted and any of the following conditions are satisfied:

- the respective deployment command is sent during a valid pulse stretch timer, which initiated by ARM signal
- the respective SPI ARM command is sent during a valid pulse stretch timer, which initiate by deployment command

During a deployment, the device turn on the respective high side (SQH) and low side (SQL) drivers for duration of t_{DEPLOY} . When a deployment is initiated, it cant be terminated, except during a reset event.

Figure 11. Deployment sequence



When a deployment-enable command is sent through SPI, the pulse stretcher shall be initiated immediately following the falling edge of CS_D. When another deployment-enable

During the deployment, L9658 turn on the respective high (SQH) and low side (SQL) drivers for tDEPLOY. Once deployment is initiated it can not be terminated. When a channel is in deployment, this particular channel shall only act upon certain SPI messages. These SPI messages and their responses are summarized in below table. The rest of the channels shall resume their operations and respond to specific SPI commands.

During a deployment, the device ignores arming commands. and does not refresh or terminate the pulse stretch timer when it receives an arming command.

Table 12. SPI transmission during a deployment

SPI MOSI	SPI MISO ⁽¹⁾	Notes
Register mode	SPI fault response	MOSI register mode message shall be ignored
Command mode	Command mode	Execute for channels not in deployment; no effect to deploying channel
Diagnostic mode	SPI fault response	MOSI diagnostic mode message shall be ignored
Monitor mode	Status response	Execute for all channels

1. SPI MISO sent in the next SPI transmission.

4.10 DEPEN

DEPEN is a deployment enable input, which is an active high input. When this pin is asserted, L9658 is able to turn on its high and low side drivers upon receiving a valid deployment command or a MOS diagnostic request. DEPEN can not interrupt a deployment that is already in-progress.

When DEPEN is negated, it inhibits the low side and the high side MOS from turning on (inhibit the deployment). When a MOS diagnostic is requested, the device executes the diagnostic even without the ability to turn on the MOS. It set the proper SPI threshold bits. SPI remains functional while this pin is pulled low.

When DEPEN is negated, SPI deploy command is prevented from initiating the pulse stretch timer. Regardless of DEPEN, SPI deploy command status bits reports the state of SPI deploy command bits sent in the previous SPI transfer. This feature is required so that the processor can diagnose SPI deploy command bits with DEPEN negated.

Regardless of DEPEN, arming signal is able to initiate the pulse stretch timer. This feature will be used for the processor to diagnose the arming signal.

When the pulse stretch timer has been running, changes in the state of DEPEN does not affect the pulse stretch timer. The pulse stretch timer is not affected regardless of the pulse stretch timer being started by an arming signal or a SPI deploy command.

A de-glitch timer is provided to DEPEN pin. The timer protects this pin against spurious glitches. The device neglects DEPEN signal if it is asserted/negated for shorter than t_{GLITCH} .